Am79530/Am79531/ Am79534/Am79535

Subscriber Line Interface Circuit

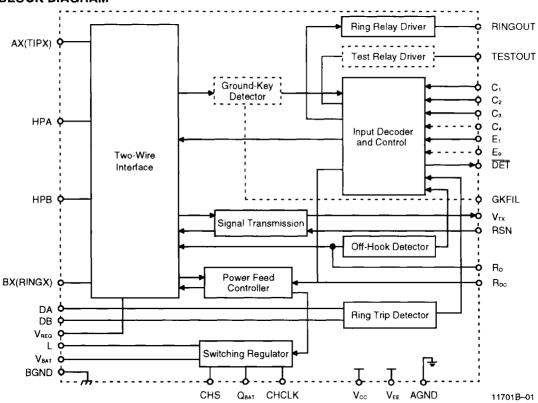
Advanced Micro Devices

DISTINCTIVE CHARACTERISTICS

- Programmable constant current feed
- Line-feed characteristics independent of battery variations
- Programmable loop detect threshold
- On-chip switching regulator for low-power dissipation
- Pin for external ground-key noise filter capacitor available

- Ground-key detect
- Low standby power
- Two-wire impedance set by single external impedance
- Polarity reversal feature
- Tip open state for ground start lines
- Test relay driver optional

BLOCK DIAGRAM



Notes: Am79530—E₀ and E₁ inputs; ring relay sourced internally to BGND; no test relay driver.

Am79531—E₀ and E₁ inputs; ring relay sourced internally to BGND; no test relay driver; ground-key filter pin.

Am79534—Eo and E1 inputs; ring and test relay drivers sourced internally to BGND.

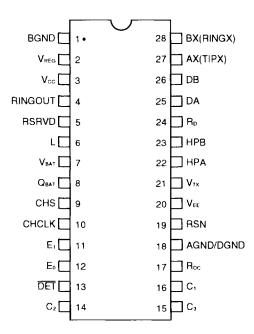
Am79535-Eo and E1 inputs; ring relay driver sourced internally to BGND; ground-key filter pin.

Current gain (K1) = 1000 for all parts.

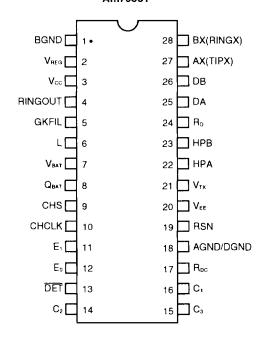
This document contains information on a product under development at Advanced Micro Devices, Inc. The information is intended to help you evaluate this product. AMD reserves the right to change or discontinue work on this proposed product without notice.

CONNECTION DIAGRAMS Top View

Am79530

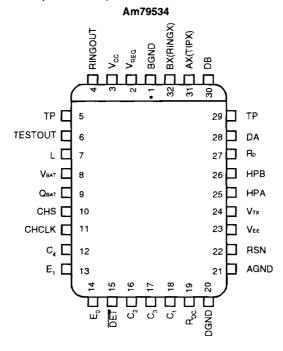


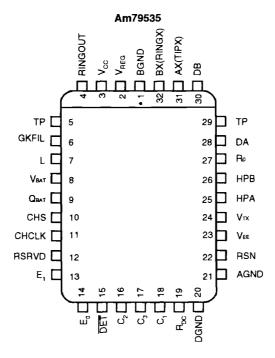
Am79531



Note: Pin 1 is marked for orientation.

CONNECTION DIAGRAMS (continued)



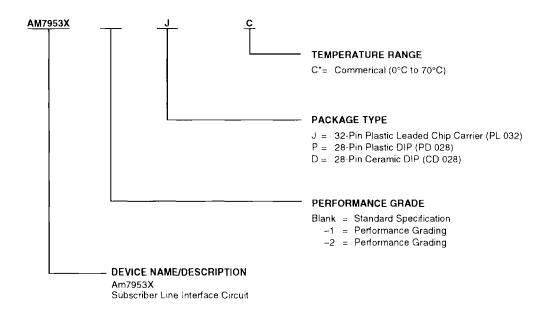


Notes: 1. Pin 1 is marked for orientation.
2. TP is a thermal conduction pin tied to substrate (Q_{BAT}).

ORDERING INFORMATION

Standard Products

AMD standard products are available in several packages and operating ranges. The order number (Valid Combination) is formed by a combination of the elements below.



Valid Combinations					
	DC, JC, PC				
AM7953X	-1DC, -1JC, -1PC				
	-2DC, -2JC, -2PC				

Valid Combinations

Valid Combinations list configurations planned to be supported in volume for this device. Consult the local AMD sales office to confirm availability of specific valid combinations, to check on newly released combinations, and to obtain additional data on AMD's standard military grade products.

^{*}The performance specifications contained in this data sheet are valid for the commercial temperature range only. See the SLIC Extended Temperature Supplement for information on industrial temperature range (-40°C to +85°C) specifications.

PIN DESCRIPTION

AGND

Ground (Am79534 and Am79535)

Analog (Quiet) ground.

DGND

Ground (Am79534 and Am79535)

Digital ground.

AGND/DGND

Ground (Am79530, Am79531)

Analog and digital ground are connected internally to a single pin.

AX(TIPX)

(Output)

Output of A(TIP) power amplifier.

BGND

Ground

Battery (power) ground.

BX(RINGX)

(Output)

Output of B(RING) power amplifier.

C3-C1

Decoder (inputs)

TTL compatible. C₃ is MSB and C₁ is LSB.

C4

Test Relay Driver Command (Input) (Am79534)

TTL compatible. A logic Low enables the driver.

CHCLK

Chopper Clock (Input)

Input to switching regulator (TTL compatible). Frequency = 256 kHz (Nominal).

CHS

Chopper Stabilization (Input)

Connection for external stabilization components.

DA

Ring Trip Negative (Input)

Negative input to ring trip comparator.

DB

Ring Trip Positive (Input)

Positive input to ring trip comparator.

DET

Detector (Output)

When enabled, a logic Low indicates that the selected detector is tripped. The detector is selected by the logic inputs (C_3 – C_1 , E_0 , E_1). The output is open-collector with a built-in 15K pull-up resistor.

E۵

Read Enable (Input)

(Am79530, Am79531, and Am79534)

A logic High enables DET. A logic Low disables DET.

E٠

Ground Key Enable (Input)

When E_0 is High, E_1 = High connects the ground-key detector to \overline{DET} , and E_1 = Low connects the off-hook or ring trip detector to \overline{DET} .

GKFII

Ground-Key Filter Capacitor Connection (Am79531 and Am79535)

An external capacitor for filtering out high-frequency noise from the ground-key loop can be connected to this pin. An internal 36K –20%, +40% resistor is provided to form an RC filter with the external capacitor.

In versions which have a GKFIL pin, 3.3 nF minimum capacitance must be connected from the GKFIL pin to ground.

HPA

A(TIP) side of high-pass filter capacitor.

HPB

B(RING) side of high-pass filter capacitor.

L

Switching Regulator Power Transistor (Output)

Connection point for filter inductor and anode of catch diode. This pin will have up to 60 V of pulse waveform on it and must be isolated from sensitive circuits. Extreme care must be taken to keep the diode connections short because of the high currents and high di/dt.

$\mathbf{Q}_{\mathsf{BAT}}$

Quiet Battery

Filtered battery supply for the signal processing circuits.

R₀

Threshold modification and filter point for the off-hook detector.

RDC

Connection point for the DC feed current programming network. The other end of the network connects to the Receiver Summing Node (RSN). The sign of V_{ROC} is minus for normal polarity and plus for reverse polarity.

RINGOUT

Ring Relay Driver (Output)

Sourcing from BGND with internal diode to Q MT



TESTOUT

Test Relay Driver (Output) (Am79534)

Sourcing from BGND with internal diode to Q_{BAT}

RSN

Receive Summing Node (Input)

The metallic current (both AC and DC) between A(TIP) and B(RING) is equal to 1000 times the current into this pin. The networks that program receive gain, two-wire impedance, and feed current all connect to this node. This node is extremely sensitive. Care should be taken to route the 256-kHz chopper clock and switch lines away from the RSN node.

VHAT

Connected to office battery supply through an external protection diode.

Ver

+5-V power supply.

W.

-5-V power supply.

V_{REG}

Regulated Voltage (Input)

Provides negative power supply for power amplifiers and connection point for inductor, filter capacitor, and chopper stabilization.

VIX

Transmit Audio (Output)

This output is a unity gain version of the AX(TIPX) and BX(RINGX) metallic voltage. The other end of the two-wire input impedance programming network connects here



ABSOLUTE MAXIMUM RATINGS Storage Temperature-55°C to +150°C V_{cc} with respect to AGND/DGND ... -0.4 V to +7.0 V V_{EE} with respect to AGND/DGND ... +0.4 V to -7.0 V V_{BAT} with respect to AGND/DGND . . . +0.4 V to -70 V Note: Rise time of V_{BAT} (dv/dt) must be limited to 27 V/µs or less when Q_{BAT} bypass = 0.33 μ F. BGND with respect to AGND/DGND +1.0 V to -3.0 V AX(TIPX) or BX(RINGX) to BGND: Continuous -70 V to +1.0 V 10 ms (F = 0.1 Hz) -70 V to +5.0 V1 μ s (F = 0.1 Hz) -90 V to +10 V 250 ns (F = 0.1 Hz) -120 V to +15 VCurrent from AX(TIP) or BX(RING) ±150 mA Voltage on RINGOUT BGND to 70 V above QBAT Voltage on TESTOUT BGND to 70 V above QRAT Current through Relay Drivers 60 mA Voltage on Ring Trip Inputs (DA and DB) V_{BAT} to 0 V Current into Ring Trip Inputs ±10 mA Peak Current into Regulator Switcher Transient Peak Off Voltage on L pin +1.0 V C4-C1, E1, CHCLK to AGND/DGND -0.4 V to V_{cc} + 0.4 V Maximum Power Dissipation, T_A (see note) ... 70°C In 28-pin ceramic DIP package 2.58 W In 28-pin plastic DIP package 1.4 W In 32-pin PLCC package 1.74 W Note: Thermal limiting circuitry on chip will shut down the circuit at a junction temperature of about 165°C. The device should never see this temperature and operation above 145°C junction temperature may degrade

device reliability. See SLIC Packaging Considerations

Stresses above those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent device failure. Functionality at or above these limits is not implied. Exposure to absolute maximum ratings for extended periods may effect device

section for more information.

reliability.

OPERATING RANGES

Commer	cial (C) Devices
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Ambient Temperature 0 $^{\circ}$ C to +70 $^{\circ}$ C
V_{cc}
$V_{\text{\tiny FE}}$ $$
$V_{\mbox{\tiny RAT}}$
AGND/DGND
BGND with respect to
AGND/DGND –100 mV to +100 mV
Load Resistance on $V_{\tau x}$ to Ground 10 Kohm Min

"-2" performance grade SLICs are functional from -40°C to +85°C. See the SLIC Extended Temperature Supplement for information on industrial temperature range (-40°C to +85°C) specifications.

Operating ranges define those limits between which the functionality of the device is guaranteed.

ELECTRICAL CHARACTERISTICS over operating range

Am79530/Am79531/Am79534/Am79535 (see Note 1)

			Prelin	ninary			
Description	Test Conditions	P.G.*	Min	Тур	Max	Uni	
Analog (V _{TX}) Output Impedance (Note 5)				3		ohn	
Analas (V.) Outrot Offact			-35		+35		
Analog (V _{⊤x}) Output Offset		-1	-30		+30	mV	
Analog (RSN) Input Impedance (Note 5)	00011-4-04111-			1	20		
Longitudinal Impedance at AX or BX	300 Hz to 3.4 kHz				35	ohr	
Overload Level	four-wire		2.4		.0.4	V-1	
$Z_{2WIN} = 600 \text{ to } 900 \text{ ohms (Note 2)}$	two-wire		-3.1		+3.1	Vpl	
Transmission Performance, two-wire in	npedance						
Two-Wire Return Loss	300 Hz to 500 Hz		26				
(See Test Circuit D)	500 Hz to 2500 Hz		26			d₿	
(Notes 5, 10)	2500 Hz to 3400 Hz		20				
Longitudinal Balance (two-wire and fou	r-wire, see Test Circuit C)						
$R_t = 600 \text{ ohms}$	00011-1-040011		48				
Longitudinal to Metallic L-T, L-4	300 Hz to 3400 Hz	-1	52				
Longitudinal to Metallic L-T and	200 Hz to 1000 Hz		63	70		d₿	
L-4 for trimmed version (consult factory)	1000 Hz to 3400 Hz	-2**	58	70			
•	200 Hz to 3400 Hz						
	(Reverse polarity)		54				
Longitudinal Signal Generation 4-L	300 Hz to 800 Hz		40			dB	
congradata orginal deneration 4-2	300 Hz to 800 Hz	-1	42			ď	
Longitudinal Current Capability	Active State			25		m/	
per Wire (Note 5)	Disable State			18		RM	
Insertion Loss (two-wire to four-wire an	d four-wire to two-wire, see	Test Circ	uits A and	B)			
Coin Assurage	0 -10 1 1-11-		-0.15		+0.15	-	
Gain Accuracy	0 dBm, 1 kHz	-1	-0.1	+0.1		dB	
Mark W.E. Water	300 Hz to 3400 Hz					ı.	
Variation with Frequency (Note 5)	Relative to 1 kHz		-0.1		+0.1	dB	
Onio Tanakina (Nata 5)	+7 dBm to -55 dBm					9	
Gain Tracking (Note 5)	Reference: 0 dBm		-0.1		+0.1	dB	
Balance Return Signal (four-wire to fou	r-wire, see Test Circuit B)						
Onin Annuary (Ninters)	0.40 4.44		-0.15		+0.15		
Gain Accuracy (Note 3)	0 dBm, 1 kHz	1	-0.1		+0.1	dB	
Washing with Francisco (Nation 2015)	300 Hz to 3400 Hz						
Variation with Frequency (Notes 3, 5)	Relative to 1 kHz		-0.1		+0.1	dB	
	+3 dBm to -55 dBm						
Gain Tracking (Note 5)	Reference: 0 dBm		-0.1		+0.1	₫B	
Group Delay (Notes 5, 12)	F = 1 kHz			5.3		μs	
Total Harmonic Distortion (two-wire to	four-wire or four-wire to two	o-wire. see	e Test Circ	uits A and	(B)		
The same state of the same to	0 dBm, 300 Hz-3.4 kHz		10010110	-64	_50		
Total Harmonic Distortion	+9 dBm, 300 Hz-3.4 kHz			-55	-40	l dB	

^{*}P.G. = Performance Grade

**All other performance parameters equivalent to −1 grade.

Normal Polarity only.

PRELIMINARY
ELECTRICAL CHARACTERISTICS (continued)

		Preliminary					
Description	Test Conditions	P.G.	Min	Тур	Max	Unit	
Idle Channel Noise				-			
				+7	+15	dBrni	
C-Message Weighted Noise	two-wire	-1		+7	+12		
(Notes 5, 7)	four-wire			+7	+15	-10	
	lour-wire	-1		+7	+12	dBrn⊄	
	two wire			-83	-75	40	
Psophometric Weighted Noise	two-wire	-1		-83	-78	dBm	
(Note 7)	four-wire			-83	-75	-15	
	10ur-wire	-1		-83	-78	dBm	
Single Frequency Out-of-Band Noise	(see Test Circuit E)						
Metallic	4 kHz to 9 kHz			-76			
(Notes 4, 5, 9)	9 kHz to 1 MHz	1		-76	Ì	dBm	
(Notes 4, 5)	256 kHz and harmonics	1		-57			
Longitudinal	1 kHz to 15 kHz			-70			
(Notes 4, 5, 9)	Above 15 kHz	1		-85		dBm	
(Notes 4, 5)	256 kHz and harmonics	1		-57			
DC Feed Currents (see Figures 1a, 1b	. 1c) Battery = -48 V						
Active Mode Loop Current Accuracy	ILOOP (nominal) = 40 mA	T	-7.5		+7.5	%	
Disable Mode	R _L = 600 ohms	1	18	20	22		
Tip Open Mode	R _L = 600 ohms	1			1.0	mA	
Open Circuit Mode	R _L = 0 ohms	1	-		1.0		
Fault Current Limit, ILIM (IAX + IBX)	AX and BX shorted to ground				130	mA	
Power Dissipation Battery = -48 V, No	ormal Polarity						
<u> </u>	- County	Ī		35	120	· ·	
On-Hook Open Circuit		-1		35	80		
0. 11 1.6: 11 14 1				135	250		
On-Hook Disable Mode		-1		135	200	l	
0 11 1 1 2 11 1				200	400	mW	
On-Hook Active Mode		-1		200	300		
Off-Hook Disable Mode	R _L = 600 ohms			500	750	1	
Off-Hook Active Mode	R _L = 600 ohms			650	1000	1	
Supply Currents							
	Open Circuit Mode	1		3.0	4.5		
V _{cc} On-Hook Supply Current	Disable Mode			6.0	10.0	mA	
	Active Mode]		7.5	12.0		
	Open Circuit Mode			1.0	2.3		
V _{EE} On-Hook Supply Current	Disable Mode			2.2	3.5	mA	
	Active Mode	-		2.7	6.0		
V _{BAT} On-Hook Supply Current	Open Circuit Mode Disable Mode			0.4 3.0	1.0 5.0	mA	
Total Carried Cappiy Culton	Active Mode			4.0	6.0	'''	

AMD PRELIMINARY ELECTRICAL CHARACTERISTICS (continued)

			Prelin	ninary		
Description	Test Conditions	P.G.	Min	Тур	Max	Unit
Power Supply Rejection Ratio (Vripple	= 50 mV RMS)					
			25	45		dB
Vcc	50 Hz to 3400 Hz	-1	30	45		
(Notes 6, 7)	0.4111-4. 50141-		22	35		dB
	3.4 kHz to 50 kHz	-1	25	35		OB.
	50 Hz to 3400 Hz		20	40		dB
V_{EE}	50 HZ 10 3400 HZ	-1	25	40		uв
(Notes 6, 7)	3.4 kHz to 50 kHz		10	25		dB
	3.4 KHZ (0 30 KHZ	-1	10	25		Q.D
	50 Hz to 3400 Hz		27	45		dB
V _{BAT}	30 112 10 3400 112	-1	30	45		40
(Notes 6, 7)	3.4 kHz to 50 kHz		20	40		dB
	3.4 KI IZ (0 30 KI IZ	-1	25	40		42
Off-Hook Detector						
Current Threshold Accuracy	I _{DET} = 365/R _D Nominal		-20		+20	%
Ground-Key Detector Thresholds, Acti	ve Mode, Battery = -48 V (see Test Ci	rcuit F)			
Ground-Key Resistance Threshold	B(Ring) to GND		2.0	5.0	10.0	Kohm
0 1/4 0 17 1 1/4/14 0)	B(Ring) to GND			9		4
Ground-Key Current Threshold (Note 8)	Midpoint to GND			9		mA
Ring Trip Detector Input						
Bias Current		T	-5	-0.05		μА
Offset Voltage (Note 11)	Source Resistance 0 to 2 Mohm		-50	0	+50	mV
Logic Inputs (C ₁ , C ₂ , C ₃ , C ₄ , E ₀ , E ₁ , and (CHCLK)	-				•
Input High Voltage	T	T	2.0			٧
Input Low Voltage					0.8	٧
Input High Current			-75		40	μА
Input Low Current			-0.4			mA
Logic Output (DET)						
Output Low Voltage	f _{ouτ} = 0.8 mA				0.4	V
Output High Voltage	l _{out} = -0.1 mA		2.4			V



SWITCHING CHARACTERISTICS Am79530/Am79531/Am79534/Am79535

	Parameter	Test Conditions	Min	Тур	Max	Unit
takdo	E_1 High to \overline{DET} High ($E_0 = 1$)	Ground-Key Detect Mode			3.8	
tgkde	E_1 High to \overline{DET} Low $(E_0 = 1)$	R∟ Open, R₃ Connected (see Test Circuit H)			1.1	μs
E_1 Low to \overline{DET} Low $(E_0 = 1)$ tshde E_1 Low to \overline{DET} High $(E_0 = 1)$				1.2		
	E_1 Low to \overline{DET} High $(E_0 = 1)$				3.8	μs
tshdd	E_0 High to \overline{DET} Low $(E_1 = 0)$	Switch Hook Detect Mode R _L = 600 ohms, R _G Open (see Test Circuit G)			1.1	
tshd0	E_0 Low to \overline{DET} High $(E_1 = 0)$		-		3.8	μs
tgkdd	E₀ High to DET Low (E₁ = 1)				1.1	
tgkd0	E_0 Low to \overline{DET} High $(E_1 = 1)$				3.8	μs

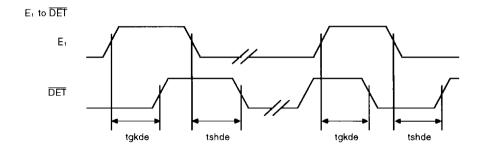
Table 1. SLIC Decoding

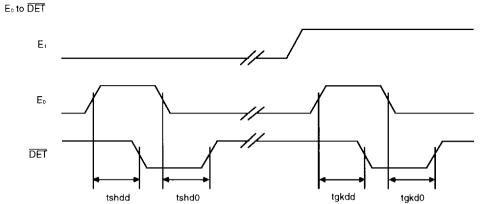
					DE	T Output
State	C,	C ₂	C ₁	Two-Wire Status	E ₀ = 1* E ₁ = 0	E ₀ = 1* E ₁ = 1
0	0	0	0	Open Circuit	Ring Trip	Ring Trip
1	0	0	1	Ringing	Ring Trip	Ring Trip
2	0	1	0	Active	Loop Det.	Ground Key
3	0	1	1	Disable	Loop Det.	Ground Key
4	1	0	0	Tip Open	Loop Det.	
5	1	0	1	Reserved	Loop Det.	_
6	1	1	0	Active Polarity Reversal	Loop Det.	Ground Key
7	1	1	1	Disable Polarity Reversal	Loop Det.	Ground Key

For the Am79530, Am79531, Am79534, and Am79535, a logic Low on E₀ disables the DET output into the open-collector state.

SWITCHING WAVEFORMS

Am79530/Am79531/Am79534/Am79535





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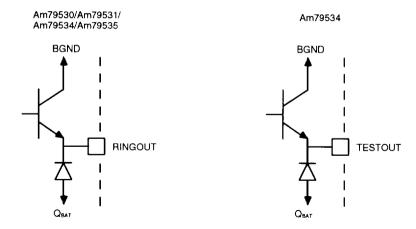
tgkd0

Note: All delays measured at 1.4-V level.

tshdd

tshd0

Relay Driver Specifications



11701B--003

Description	Test Conditions	Min	Тур	Max	Unit
Relay Driver Outpu	uts (RINGOUT, TESTOUT)				
On Voltage	50 mA Source	BGND -2	BGND-0.95		V
Off Leakage			0.5	100	μА
Clamp Voltage	50 mA Sink	Q _{BAT} –2			V

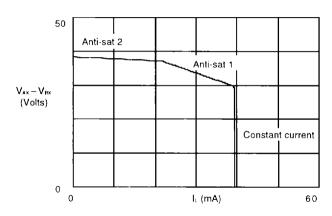
Notes:

- Unless otherwise noted, test conditions are: Battery = -48 V, V_{cc} = +5 V, V_{EE} = -5 V, R_L = 600 ohms, C_{HP} = 0.22 μF, R_{Dc1} = R_{Dc2} = 31.25K, C_{Dc} = 0.1 μF, R_d = 51.1K, no fuse resistors, two-wire AC output impedance, programming impedance (Z_T) = 600K resistive, receive input summing impedance (Z_{TX}) = 300K resistive. (See Table 2 for component formulas.)
- 2. Overload level is defined when THD = 1%.
- Balance return signal is the signal generated at V_{TX} by V_{RX}. This spec assumes that the two-wire AC load impedance matches the impedance programmed by Z_T.
- 4. These tests are performed with a longitudinal impedance of 90 ohms and metallic impedance of 300 ohms for frequencies below 12 kHz and 135 ohms for frequencies greater than 12 kHz. These tests are extremely sensitive to circuit board layout.
- 5. Not tested in production. This parameter is guaranteed by characterization or correlation to other tests.
- 6. This parameter is tested at 1 kHz in production. Performance at other frequencies is guaranteed by characterization.
- When the SLIC is in the Anti-sat 2 operating region, this parameter will be degraded. The exact degradation will depend
 on system design. The Anti-sat 2 region occurs at high loop resistances when |V_{BAT}| |V_{AX} V_{BX}| is less than approximately
 11 V
- 8. "Midpoint" is defined as the connection point between two 300-ohm series resistors connected between A(TIP) and B(RING).
- 9. Fundamental and harmonics from 256-kHz switch-regulator chopper are not included.
- 10. Assumes the following Z_T network: V_{TX} 300K 300K 300K 300K 300F
- 11. Tested with 0 ohm source impedance. Two Mohms is specified for system design purposes only.
- Group delay can be considerably reduced by using a Z_T network such as that shown in Note 10 above. The network will reduce
 the group delay to less than 2 μs. The effect of group delay on linecard performance may be compensated for by using SLAC
 or DSLAC devices.

Table 2. User-Programmable Components

Table 2. 03	Table 2. Oser-1 Togrammable Components					
$Z_{\tau} = 1000(Z_{2WIN} - 2R_F)$	Z_T is connected between the V_{Tx} and RSN pins. The fuse resistors are R_F , and Z_{ZWN} is the desired two-wire AC input impedance. When computing Z_T , the internal current amplifier pole and any external stray capacitance between V_{Tx} and RSN must be taken into account.					
$Z_{RX} = -\frac{Z_L}{G42L} - \frac{1000 Z_T}{Z_T + 1000(Z_L + 2R_F)}$	Z_{FX} is connected from V_{FX} to the RSN pin and Z_{T} is defined above and G42L is the desired receive gain.					
$R_{DC1} + R_{DC2} = 2500/I_{FFED}$ $C_{DC} = (1.5 \text{ ms})(R_{DC1} + R_{DC2})/(R_{DC1}R_{DC2})$	R_{DG1} , R_{DG2} , and C_{DG} form the network connected to the R_{DG} pin. R_{DG1} and R_{DG2} are approximately equal.					
$R_0 = 365/I_T$, $C_0 = 0.5 \text{ ms/R}_0$	R_0 and C_0 form the network connected from R_0 to -5 V, and IT is the threshold current between on-hook and off-hook.					

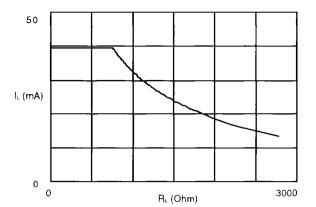
$$V_{BAT} = -47.3 \text{ V}$$
 $R_{DC1} + R_{DC2} = R_{DC} = 62.5 \text{K}$



$$\label{eq:constant current region:} \begin{split} I_L &= \frac{2500}{R_{bc}} \\ &\quad \text{Anti-sat 1 region:} \quad V_{\text{AX-BX}} = 45.78 - \frac{R_{bc}}{152.6} \quad I_L \\ &\quad \text{Anti-sat 2 region:} \quad V_{\text{AX-BX}} = 1.067 \mid V_{\text{PAT}} \mid -12.22 - \left(0.0128 + \frac{R_{bc}}{1523}\right) \mid_L \end{split}$$
 See Figure 1c.

11701B-004

Figure 1a. Load Line (Typical)



Load Current versus Load Resistance—Am79530/Am79531/Am79534/Am79535

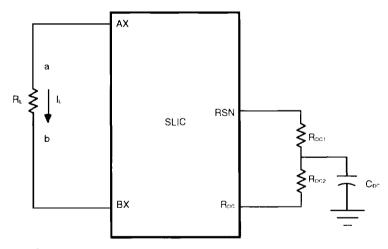
 $V_{BAT} = -47.3 \text{ V}$

 $R_{DC} = 62.5K$

See Figure 1c.

11701B-005

Figure 1b. Feed Characteristics (Typical)

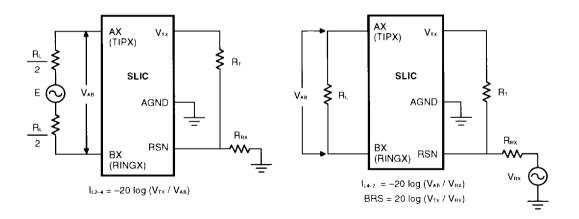


Current programmed by R_{DC1} and R_{pc2} .

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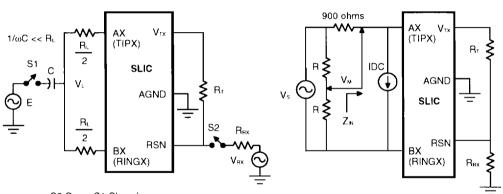
Figure 1c. Feed Programming

TEST CIRCUITS



A. Two-to-Four Wire Insertion Loss

B. Four-to-Two Wire Insertion Loss and Balance Return Signal



S2 Open, S1 Closed:

L-T Long. Bal. = 20 log (V_{AB}/E) L-4 Long. Rej. = 20 log ($V_{\tau x}/E$)

S2 Closed, S1 Open:

4-L Long. Sig. Gen. = 20 log (V_L/V_{RX})

C. Longitudinal Balance

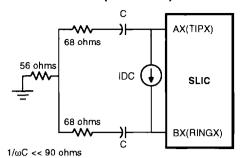
Z_b: The desired impedance (e.g., the characteristic impedance of the line).

Return Loss = $-20 \log (2 V_M/V_s)$

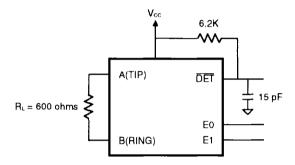
D. Two-Wire Return Loss Test Circuit

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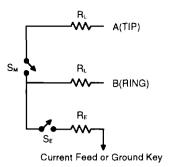
TEST CIRCUITS (continued)



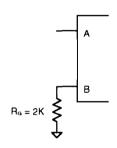
E. Single-Frequency Noise



G. Loop Detector Switching



F. Ground-Key Detection



H. Ground-Key Switching

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